Study of Microstructure of Low-Temperature Plasma-Nitrided AISI 304 Stainless Steel

XIAOLEI XU, LIANG WANG, ZHIWEI YU, JIANBING QIANG, and ZUKUN HEI

The microstructure of the low-temperature plasma-nitrided layer on AISI 304 austenitic stainless steel was studied by transmission electron microscopy (TEM). The results show that the surface of the layer consists of a supersaturated solid solution (γ'_{N}) based on the γ' -Fe₄N phase whose electron diffraction pattern (EDP) has a strong diffuse scattering effect resulting from supersaturating nitrogen (above 20 at. pct) and $\langle 110 \rangle$ streaks arising from matrix elastic strain due to the formation of paired or clustered Cr-N. The latter is due to the N above the 20 at. pct γ' -Fe₄N–phase value and leads to a lattice parameter that is greater than that of the γ' -Fe₄N phase. The subsurface of the layer is composed of a supersaturated solid solution based on γ -austenite, which is an expanded austenite, γ_N . Its morphology shows the basketweave or "tweedlike" contrast consisting of so-called stacking fault precipitates having twin relationships with the matrix whose EDP shows diffuse scattering streaks with certain directions. The ε martensite transformation was observed in the subsurface of the layer. The increase in stacking faults compared with the original stainless steel and formation of ε martensite in the subsurface of the layer indicate that nitrogen lowers the stacking fault energy of austenite.

STAINLESS steel is widely used in chemical, food, and

ordil address this issue using transmission electron micros-

there industries due to its corrosion-resistance properties.

However, because of its low hardness or tions $[5-8]$ the exact nature of the microstructural changes responsible for this improvement is not very well understood. Using most techniques, the lattice parameter of the so-called **II. EXPERIMENT METHODS** γ_N is greater than that of the γ' -Fe₄N ($a = 0.379$, nm) and Its nitrogen content more than 20 at. pct.^[7,8] It is uncertain The AISI 304 stainless steels annealed were used in this whether the supersaturated solid solution is based on the α' -
whether the supersaturated solid whether the supersaturated solid solution is based on the γ' -
Fe₄N or γ -austenite or on both. In other words, there would
be two kinds of supersaturated solid solution respectively
based on either γ' -Fe₄N or structure. The former has nitrogen atoms occupying octahe-
dral interstitial sites of cube center in a fully ordered manner,
and the latter has nitrogen atoms randomly distributed
schematic of the nitriding system used in

I. INTRODUCTION throughout all interstitial octahedral sites. In this article, we

and the latter has nitrogen atoms randomly distributed schematic of the nitriding system used in this work is shown
in Figure 1. The samples were plasma nitrided for 2 hours at 400 °C to about 420 °C in a $4N_2$: H_2 atmosphere at a total pressure of 0.3 Pa. The samples for TEM were prepared by XIAOLEI XU, LIANG WANG, and ZHIWEI YU, Associate Professors,

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are with the Institute of Metal and Technology, Dalian Maritime University,
 $\frac{10.4 \text{ m}}{40 \mu$ Dalian 116024, People's Republic of China. the material conversion, to make the thin foil for the layer surface, and from layer-
balian 116024, People's Republic of China. Manuscript submitted December 11, 1998. Surface side to make the thin foils for the subsurface 8 to

Fig. 1—Plasma nitriding system.

about 9 μ m below surface and matrix. The TEM observations were made with a Hitachi 800 transmission electron (*a*) microscope at an acceleration voltage of 175 kV.

The phases present in the plasma-nitrided layer were determined by glancing angle X-ray diffraction (XRD) on a Rigaku D/max-IIIA diffractometer. The radiation used was Cu $K\alpha$ ($\lambda = 0.1542$ nm) at incident angles of 10 deg.

III. RESULTS AND DISCUSSIONS

A. *XRD Results*

X-ray difraction patterns of the plasma-nitrided and untreated samples are shown in Figure 2. It is demonstrated that the untreated sample is single-phase γ -austenite, and its peaks are sharp, which is typical of annealed materials. For the plasma-nitrided sample, all peaks were shifted to the lower angles and were broadened considerably. Peaks the lower angles and were broadened considerably. Peaks 2θ (deg)
appear at $2\theta = 39.55$ deg, 45.45 deg, and 67.65 deg corres-
ponding to plane spacings of $d = 0.228$ nm, $d = 0.199$ nm, (*b*) and $d = 0.138$ nm, respectively. The shift is associated with Fig. 2—X-ray diffraction patterns for untreated and plasma-nitrided 304 the expanded fcc phase caused by the pitrogen remaining stainless steel: (*a*) untreate the expanded fcc phase caused by the nitrogen remaining. in solid solution in the fcc lattice. The broadening for peaks results from the inhomogeneous stress produced by supersaturating nitrogen and nonuniform nitrogen content over the depth range of XRD.[7] The XRD results show that the nitrided layer is mainly composed of supersaturated solid solutions with an expanded fcc structure, and the lattice parameter of the supersaturated lattice determined by XRD surpasses that of the γ' -Fe₄N phase. Because the intensity of X-ray is much lower than the intensity of electron diffraction and is more restricted by atomic number than the latter, the ordering diffraction peaks related to the arrangement role of the light atoms (nitrogen atoms) in the lattice are not detectable by XRD. It is difficult to determine whether the supersaturated solid solution is based on γ' -Fe₄N or γ austenite by XRD or whether there are two kinds of solid solution based on the different phases at different depths from the surface.

A scanning electron microscopy (SEM) morphology giv-
 etc. the ontire nitriding zone is shown in Figure 3 (observed H_2O (80 mL). ing the entire nitriding zone is shown in Figure 3 (observed in a JEOL* 35 CF scanning microscope). Thickness of the

*JEOL is a trademark of Japan Electron Optics Ltd., Tokyo.

nitrided layer is about 10 μ m. The TEM specimens were about 9 μ m below surface (marked A and B).

B. *TEM Results*
A scanning electron microscopy (SEM) morphology giv-
A scanning electron microscopy (SEM) morphology giv-
etching solution: CuSO₄·5H₂O (20 g) + HCl (100 mL) + H₂SO₄ (5 mL)

located on the layer surface and in the subsurface at 8 to

determining accurately the camera constant $(L\lambda)$ using the ing technology, such as pure iron nitrided at 550° C (Figure 5) diffraction pattern in Figure $4(b)$ shows an obvious diffuse order usually exhibit diffuse intensity maxima in electron

Fig. 4—Microstructure of the nitrided layer surface (γ_N) and its electron
diffraction pattern: (a) bright-field image and (b) EDP.
diffraction pattern: (a) bright-field image and (b) EDP.
diffraction pattern: (a) bright

reflections in the EDP of Figure 4(b) are not as clear as the 1. *Microstructure on the surface of the nitrided layer.* ones in Figure 5(b). It is suggested that the supersaturated The microstructure of the layer surface is shown in Figure solid solution with short-range order is based on γ' -Fe₄N, 4(a). Its electron diffraction pattern (Figure 4(b)) indicates but supersaturating with nitrogen beyond 20 at. pct does not that it is an ordered fcc phase similar to the γ' -Fe₄N phase, make the long-range order of γ' -Fe₄N change. It is well
but the lattice parameter is larger than that of γ' -Fe₄N. After known that the stable $\$ but the lattice parameter is larger than that of γ' -Fe₄N. After known that the stable γ' -Fe₄N has a very narrow nitrogen-
determining accurately the camera constant (*L* λ) using the concentration range (5.30 electron diffraction rings of Au, the lattice parameter of the 20 at. pct. The AISI 304 stainless steel contains a high fcc phase was determined from the EDP as 0.394 to about concentration of Cr atoms and the bonding between Cr and 0.400 nm, which is in good agreement with the results of \blacksquare N is greater than between Fe and N or Ni and N, ^[8] which XRD. More importantly, compared with the electron diffrac- is consistent with the formation trend of CrN at high temperation pattern of γ' -Fe₄N obtained by the usual plasma-nitrid-
ing technology, such as pure iron nitrided at 550 °C (Figure 5) low temperature so that pairs or clusters of the Cr and N or other ferrite steels, $\left[12\right]$ in which there are clear superlattice could form without precipitation of the compound CrN. The reflections resulting from the nitrogen atoms at octahedral Cr atoms occupy substitutively fcc lattice sites and combine interstitials of cube center besides the fundamental reflec- with nitrogen atoms clustering at octahedral interstitials at tions resulting from the Fe atoms at fcc lattice, the electron the midpoints of cube edges of $\{001\}_{\gamma' \text{-FeaN}}$ to form Cr-N diffraction pattern in Figure 4(b) shows an obvious diffuse pairs or clusters. It is the prese scattering effect in the form of the broadening of the funda-
mental reflections and the diffuse scattering streaks along ble. In fact, the image contrast for the supersaturated γ' -Fe₄N possible. In fact, the image contrast for the supersaturated γ' - $\langle 100 \rangle$. It is well known that solid solutions with short-range Fe₄N is quite different from the γ' -Fe₄N obtained by plasma-order usually exhibit diffuse intensity maxima in electron intriding pure iron (Figure diffraction patterns.^[13] It should be noted that the superlattice Figure $\overline{4}$ (a), good diffraction contrast cannot be observed, and no matter what the thickness of the foil is or the orientation of the grain observed is, good contrast could not be obtained. It seems that it has the characteristic of an amorphous phase contrast to some extent. The Cr-N pairs or clusters in the supersaturated solid solution is short-range ordering but long-range disordering due to the random site occupation of the Cr, which contributes to the poor diffraction contrast and diffuse scattering effect. The poor diffraction contrast and corresponding diffuse scattering effects observed and the lattice parameter greater than γ' -Fe₄N demonstrate that a metastable supersaturated solid solution has formed on the layer surface and is based on γ' -Fe₄N. We suggest this phase should be known as γ_N to distinguish it from γ_N . Additionally, the electron diffraction pattern (Figure 4(b)) shows [110] and [$\overline{1}10$] streaks at the (020) and (200) reflections. Streaks can arise in diffraction patterns because of modification to the shape of reciprocal lattice points arising from either shape effects of crystal defects and precipitates or from the lattice strain associated with them, *i.e.*, elastic strain effects. Often the elastic distortion of the matrix resulting from a coherent misfitting produces diffuse scattering in reciprocal space in the direction of the distortion. It is difficult to separate streaks resulting from the elastic distortion of the matrix from the shape effects of the precipitates because they occur in the same direction. The pairs or clusters of Cr-N on {100} matrix planes can produce shape streaks in reciprocal space in $\langle 100 \rangle$. However the coherency strains are shear strains in $\langle 110\rangle^*$ and produce streaks parallel to $\langle 110 \rangle$ in reciprocal space. The streaks resulting from the matrix elastic strain also demonstrate that the supersaturated solid solution (γ_N) contains Cr-N clusters with short-range ordering, and these form on the layer surface.

2. *Microstructure in the subsurface of the nitrided layer*

The microstructure of the subsurface and its electron diffraction pattern are shown in Figure 6. The EDP indicates that it is an fcc phase, but the lattice parameter is greater than that of the γ -austenite, attaining 0.370 nm but less than that of γ' -Fe₄N. There are no superlattice reflections. This fcc phase should be considered to be γ_N phase, which is the supersaturated solid solution of nitrogen in γ -austenite. It should be noted that there are diffuse scattering streaks with certain directions in the EDP. The images exhibit a distinctive basketweave or "tweedlike" contrast consisting of two sets
of Eig. 6—Microstructure of the subsurface (γ_N) with striations of the stacking
of striations. The inspection of the diffraction pattern reveals
fault and elect two components of diffuse scattering (at the fundamental reflections) normal to each set of striations. The diffuse directions should be interaction lines of the diffuse reciprocal plane and reciprocal plane photographed, or the striations is related to the orientation between the {111} planes and of the basketweave should be the intersection line of the the foil plane, and it is the real width only when the $\{111\}$ diffuse plane with the foil plane. By trace analysis, the planes are normal to the foil plane. When the {111} planes directions of striations are just the intersection directions of are not normal to the foil plane, the width in the image must {111} planes with the foil plane. In Figure 6, the intersection be wider than the real width. line for (111) with (112) is [312] and (111) with (112) is The described trace analysis and the corresponding micro- [132], and the angle between [312] and [132] is 44.89 deg, structure and EDP demonstrate that stacking faults are promwhich is identical with the angle between striations (indi-
cated in Figure 6(a)). Although it is difficult to measure the stacking fault precipitates form, whose morphology seems cated in Figure $6(a)$). Although it is difficult to measure the length of the diffuse streaks, it is expected that the length to exhibit the precipitation contrast, and two sets of striations is related to striation width, which is related to the thickness seem to be the precipitates, but they are only stacking faults. of the striations. The width for the striations in the image By tilting the specimen, it has been found that stacking fault

Fig. 7—Microstructure of the subsurface showing γ_N twin and its electron diffraction pattern: (*a*) bright-field image, (*b*) dark-field image (*g* = 002₇(A), $g = 002_T(B)$, and (*c*) EDP.

precipitate with two different directions are two variants of alternate matrix plane {111} in the lower stacking fault γ_N (shown by arrows), which have twin relationships with energy alloy. It is suggested that supersaturating nitrogen the γ_N matrix (Figure 7). The variants should be considered may lower the stacking fault energy to the γ_N matrix (Figure 7). The variants should be considered as the deformed twins induced by the stress resulting from supersaturating nitrogen. Stacking fault precipitates or de-
formed twins have a random stacking fault arrangement. It to the marstensite transformation induced by hydrogen.^[11] is interesting that ε martensite was observed in the subsur-
face layer (Figure 8), which is not randomly faulted fcc, such with one in the strain-induced transformation and hydrogen face layer (Figure 8), which is not randomly faulted fcc, such with one in the strain-induced transformation and hydrogen as stacking fault precipitates or deformed twins described induced.^[10,11] All in all, the format previously, but a perfect hcp phase.^[10] From Figure 8, the observation of extensive stacking faults in nitrided material two ε variants (indicated by arrows) form on {111} γ_N are good evidence that the nitrogen lowers the stacking fault whose morphology is similar to the stacking fault precipitate energy of austenitic stainless steel. described previously. In fact, the striations of stacking faults would nucleate the ε phase. When the randomly faulted fcc develop into the regularly faulted fcc, an hcp phase with an 3. *Microstructure of the matrix*
ideal *c/a* ratio would form. In fact, the *e* martensite would The microstructure of the matrix is shown in Figure 9. It ideal c/a ratio would form. In fact, the ε martensite would form by the glide of Shockley partial dislocations on each is apparent that it is quite different from that of the γ_N phase.

that the strain associated with nitrogen in solution causes to the marstensite transformation induced by hydrogen.^[11] induced.^[10,11] All in all, the formation of the ε phase and

Fig. 8—Microstructure of the subsurface showing ε martensite and electron diffraction pattern: (*a*) bright-field image, (*b*) dark-field image ($g = 010$ _a, $g = 0110_b$), and (c) EDP.

It exhibits the characteristic of an annealed structure without an expanded austenite, γ_N . The microstructure shows bas-
stacking fault precipitates and formation of ε martensite.
ketweave or tweedlike morphology,

- rated solid solution γ' -Fe₄N-type structure with additional short-range order Cr-N pairs or clusters γ'_{N} . Its electron diffraction pattern demonstrates strong diffuse scattering effects, and its lattice parameter is significantly
greater than that of γ' -Fe₄N.
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- 2. The subsurface of the nitrided layer consists of the supersat-

This project was functed solid solution γ -austenite-type structure, which is Science Foundation. urated solid solution γ -austenite-type structure, which is

ketweave or tweedlike morphology, which are striations of stacking faults or deformed twins and ε -martensite.

3. The observation of extensive stacking faults and forma- **IV. CONCLUSIONS** tion of ε -martensite indicate that nitrogen in solid solu-1. The surface of the nitrided layer consists of the supersatu-

tion lowers the stacking fault energy of austenite in 304

rated solid solution γ' -Fe N-type structure with addi-

stainless steel.

Fig. 9—Microstructure and electron diffraction pattern of matrix (a nitrided 304 stainless steel): (*a*) morphology and (*b*) EDP.

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